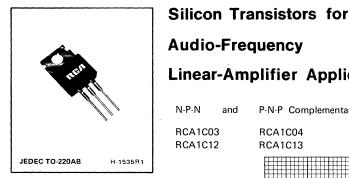


Power Transistors

RCA1C03 RCA1C12 RCA1C04 **RCA1C13**



Audio-Frequency

Linear-Amplifier Applications

N-P-N and **RCA1C03 RCA1C12**

P-N-P Complementary Types

RCA1C04 RCA1C13

RCA1C03, RCA1C04, RCA1C12, and RCA1C13 are complementary silicon n-p-n and p-n-p transistors especially characterized for audio-amplifier applications. These devices, singly or in pairs in complementary- or quasi-complementarysymmetry circuits, are particularly useful as drivers or predrivers. They may also be used in audio power amplifiers, linear modulators, servo amplifiers, and operational amplifiers. The units are supplied in the JEDEC TO-220AB version of the plastic VERSAWATT package.

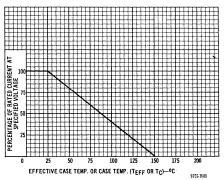


Fig. 1- Derating curve for all types.

MAXIMUM RATINGS, Absolute-Maximum Values:	RCA1C03	RCA1C04	RCA1C12	RCA1C13	
COLLECTOR-TO-BASE VOLTAGEV _{CBO}	120	-120	140		v
COLLECTOR-TO-EMITTER SUSTAINING VOLTAGE:					
With base open \ldots VCEO	100	-100	120	-120	v
With external base-to-emitter resistance (R _{BE}) = 100 Ω V _{CER}	120	-120	140	140	V
EMITTER-TO-BASE VOLTAGE V _{EBO}	5	5	5	5	ν
CONTINUOUS COLLECTOR CURRENT IC	4	-4	4	-4	Α
CONTINUOUS BASE CURRENT I _B	2	-2	2	-2	А
TRANSISTOR DISSIPATION: PT					
At case temperatures up to 25 ⁰ C	40	40	40	40	W
At case temperatures above 25°C	4	See F	ig. 1		
TEMPERATURE RANGE: Storage and Operating (Junction) PIN TEMPERATURE (During Soldering):	◀	—— –65 to	+150	••••	٥C
At distances \geq 1/32 in. (0.8 mm) from seating plane for 10 s max.	4	23			°C

Type RCA1C03 Package: JEDEC TO-220AB Construction: Silicon n-p-n, epitaxial

ELECTRICAL CHARACTERISTICS, At Case Temperature $(T_C) = 25^{\circ}C$ Unless Otherwise Specified

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS		UNITS
CHARACTERISTIC			MIN.	MAX.	
Collector Cutoff Gurrent:					
With external base-to-emitter resistance (RBE)	ICER	V _{CE} ≈ 110 V, R _{BE} = 100Ω		1	mA
Emitter Cutoff Current:					
With collector open	¹ EBO	V _{EB} ≈ 5 V, I _C = 0	-	1	mA
Collector-to-Emitter Voltage :					
With base open	VCEO	IC = 0.1 A, IB = 0	100	-	v
Gain Bandwidth Product	fT	I _C = 0.5 A, V _{CE} = 4 V	4		MHz
DC Forward-Current Transfer Ratio	hFE	IC = 1 A, VCE = 4 V	50	250	
Collector-to-Emitter Saturation Voltage	V _{CE} (sat)	IC = 1 A, IB = 0.1 A	-	1	V
Base-to-Emitter Voltage	VBE	IC = 1 A, VCE = 4 V	-	1.5	V
Second-Breakdown Collector Current:					
With base forward biased	IS/b	V _{CE} = 40 V, t = 0.4 s	1		А

For characteristics curves and test conditions, refer to published data for prototype 2N6293 (File 542).

Type RCA1C04 Package: JEDEC TO-220AB Construction: Silicon p-n-p, epitaxial

ELECTRICAL CHARACTERISTICS, At Case Temperature $(T_C) = 25^{\circ}C$ Unless Otherwise Specified

	CVMDOL	TEST CONDITIONS	LIMITS		
CHARACTERISTIC	SYMBOL	TEST CONDITIONS	MIN.	MAX.	UNITS
Collector Cutoff Current:					
With external base-to-emitter resistance (RBE)	ICER	$V_{CE} = -110 \text{ V}, \text{ R}_{BE} = 100 \Omega$	-	-1	mA
Emitter Cutoff Current:					
With collector open	IEBO	V _{EB} = -5 V, I _C = 0	-	-1	mA
Collector-to-Emitter Voltage:					
With base open	VCEO	I _C = -0:1 A, I _B = 0	-100	-	v
Gain Bandwidth Product	fT	$I_{C} = -0.5 \text{ A}, V_{CE} = -4 \text{ V}$	10	1	MHz
DC Forward-Current Transfer Ratio	hFE	IC = -1 A, VCE = -4 V	50	250	
Collector-to-Emitter Saturation Voltage	VCE(sat)	IC = -1 A, IB = -0.1 A	-	-1	V
Base-to-Emitter Voltage	VBE	IC = -1 A, VCE = -4 V	-	-1.5	V
Second-Breakdown Collector Current:					
With base forward biased	IS/b	VCE = -40 V, t = 0.4 s	-1	-	А

For characteristics curves and test conditions, refer to published data for prototype 2N6476 (File 676).

TERMINAL CONNECTIONS

- Lead 1 Base Lead 2 – Collector Lead 3 – Emitter
- Lead 4 Collector

Package: JEDEC TO-220AB Construction: Silicon n-p-n, epitaxial

ELECTRICAL CHARACTERISTICS, At Case Temperature $(T_C) = 25^{\circ}C$ Unless Otherwise Specified

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS		LINUTO
CHARACTERISTIC	HARACTERISTIC SYMBOL TEST CONDITIONS		MIN.	MAX.	UNITS
Collector Cutoff Current: With external base-to-emitter resistance (R _{BE})	ICER	V_{CE} = 90 V, R_{BE} = 100 Ω	_	100	μΑ
Emitter Cutoff Current: With collector open	^I EBO	V _{EB} = 5 V, I _C = 0	-	1	mA
Collector-to-Emitter Voltage: With base open	V _{CEO}	I _C = 0.1 A, I _B = 0	120	-	v
Collector-to-Emitter Voltage: With external base-to-emitter resistance (R _{BE})	V _{CER}	I _C = 0.1 A, R _{BE} = 100 Ω	140	-	v
Gain Bandwidth Product	fT	I _C = 0.5 A, V _{CE} = 4 V	4		MHz
DC Forward-Current Transfer Ratio	hFE	I _C = 1 A, V _{CE} = 2 V	40	250	
Base-to-Emitter Voltage	V _{BE}	I _C = 1 A, V _{CE} = 2 V	-	1.2	v
Second-Breakdown Collector Current: With base forward biased	I _{S/b}	V _{CE} = 60 V, t = 0.4 s	0.66	-	A

For characteristics curves and test conditions, refer to published data for prototype 2N6474 (File 676).

Type RCA1C13

Package: JEDEC TO-220AB Construction: Silicon p-n-p, epitaxial

ELECTRICAL CHARACTERISTICS, At Case Temperature $(T_C) = 25^{\circ}C$ Unless Otherwise Specified

			LIMITS		
CHARACTERISTIC	SYMBOL	TEST CONDITIONS	MIN.	MAX.	UNITS
Collector Cutoff Current: With external base-to-emitter resistance (R _{BE})	ICER	V _{CE} = –90 V, R _{BE} = 100 Ω	_	-100	μΑ
Emitter Cutoff Current: With collector open	^I EBO	$V_{EB} = -5 V, I_{C} = 0$		-1	mA
Collector-to-Emitter Voltage: With base open	V _{CEO}	I _C = -0.1 A, I _B = 0	-120	_	·. v
Collector-to-Emitter Voltage: With external base-to-emitter resistance (R _{BE})	V _{CER}	I _C = -0.1 A, R _{BE} = 100 Ω	-140	· _	V
Gain Bandwidth Product	fT	I _C = -0.5 A, V _{CE} = -4 V	10	-	MHz
DC Forward-Current Transfer Ratio	hFE	I _C = -1 A, V _{CE} = -2 V	40	250	
Base-to-Emitter Voltage	VBE	I _C = -1 A, V _{CE} = -2 V	-	-1.2	· V
Second-Breakdown Collector Current: With base forward biased	I _{S/b}	V _{CE} = -60 V, t = 0.4 s	-0.66	_	А

For characteristics curves and test conditions, refer to published data for prototype 2N6476 (File 676).